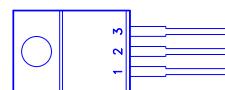
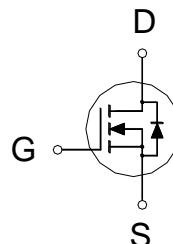


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P2206BT
TO-220
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	22.5mΩ	35A



1. GATE
-
2. DRAIN
-
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	60	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	35	A
	$T_C = 100^\circ C$		22	
Pulsed Drain Current ¹		I_{DM}	100	
Avalanche Current		I_{AS}	26	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	33.8	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	62.5	W
	$T_C = 100^\circ C$		25	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2	
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.3	1.75	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48V, V_{GS} = 0V$			1	μA
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 12A$		20	30	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$		17.5	22.5	

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 20A$	45		S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	1042		pF
Output Capacitance	C_{oss}		126		
Reverse Transfer Capacitance	C_{rss}		88		
Gate Resistance	R_g		1		
Total Gate Charge ²	Q_g	$V_{DS} = 30V, I_D = 20A$	25		nC
Gate-Source Charge ²	Q_{gs}		14		
Gate-Drain Charge ²	Q_{gd}		3.6		
Turn-On Delay Time ²	$t_{d(on)}$		9.1		
Rise Time ²	t_r	$V_{DD} = 30V,$ $I_D \approx 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	39		nS
Turn-Off Delay Time ²	$t_{d(off)}$		23		
Fall Time ²	t_f		101		
			33		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current ³	I_S			35	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$		1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 20A, dI_F/dt = 100A/\mu s$	20		nS
Reverse Recovery Charge	Q_{rr}		11		nC

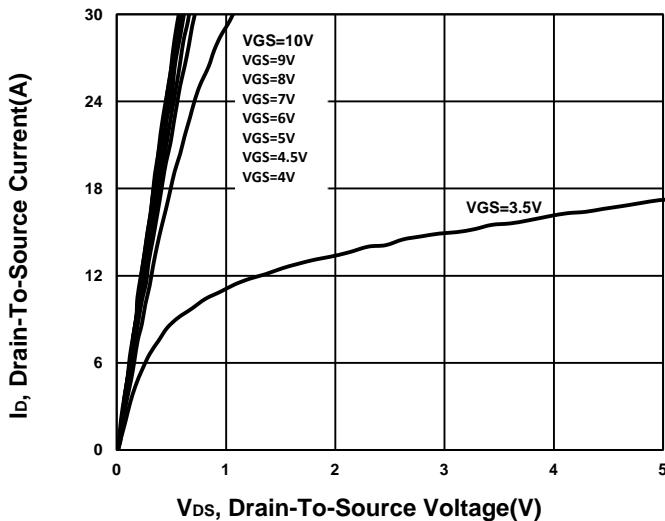
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

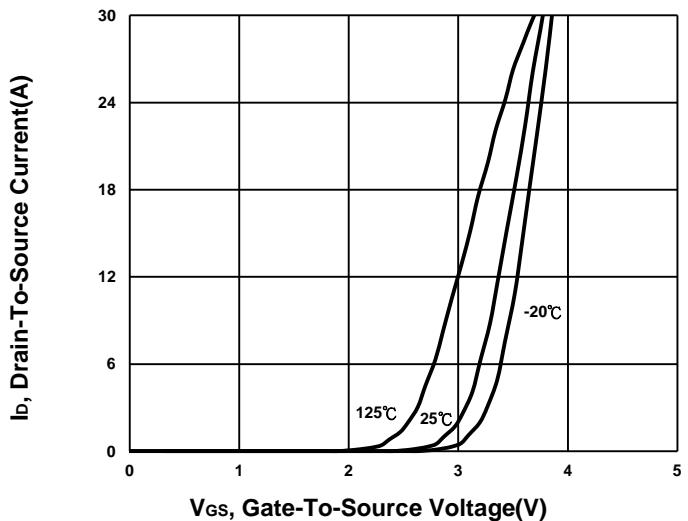
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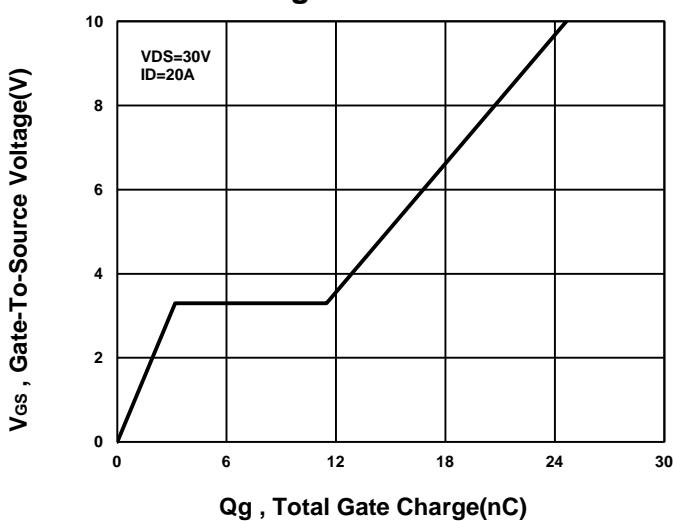
Output Characteristics



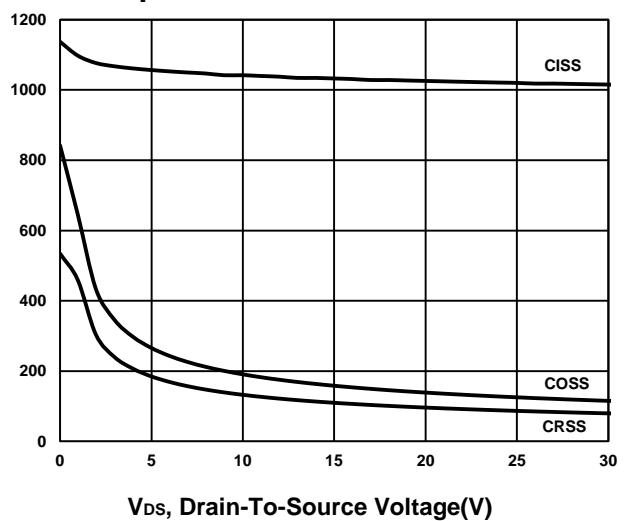
Transfer Characteristics



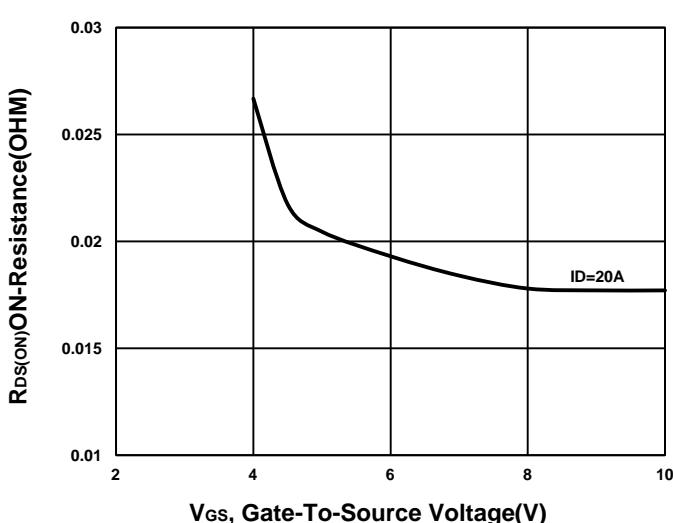
Gate charge Characteristics



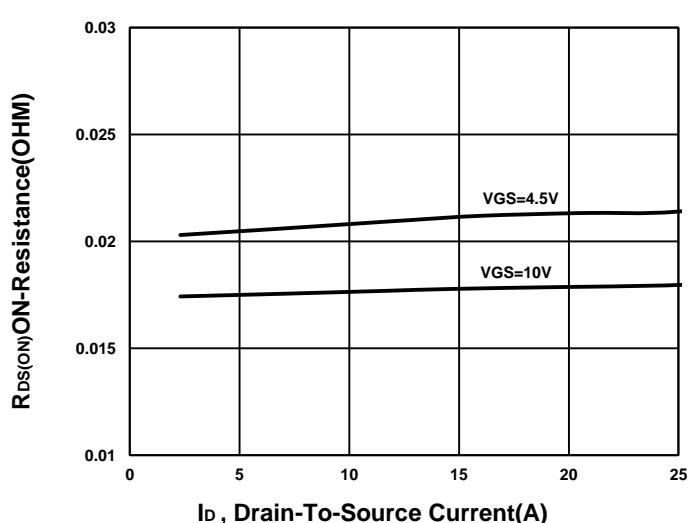
Capacitance Characteristic

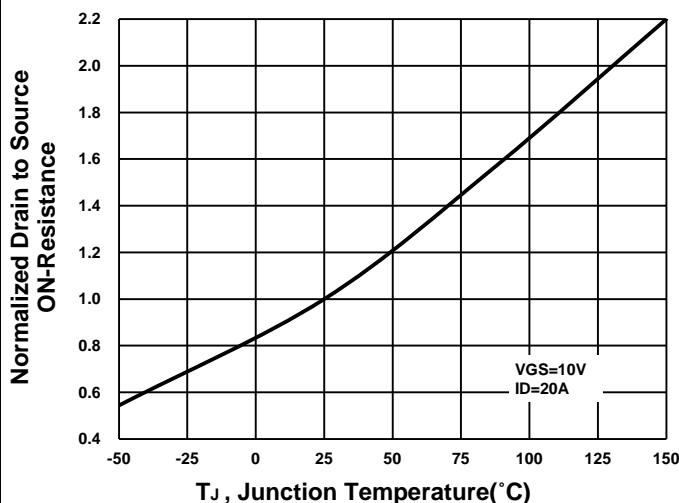
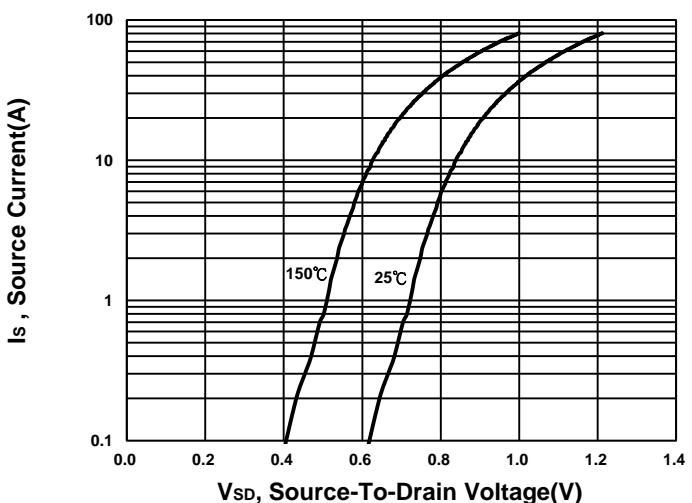
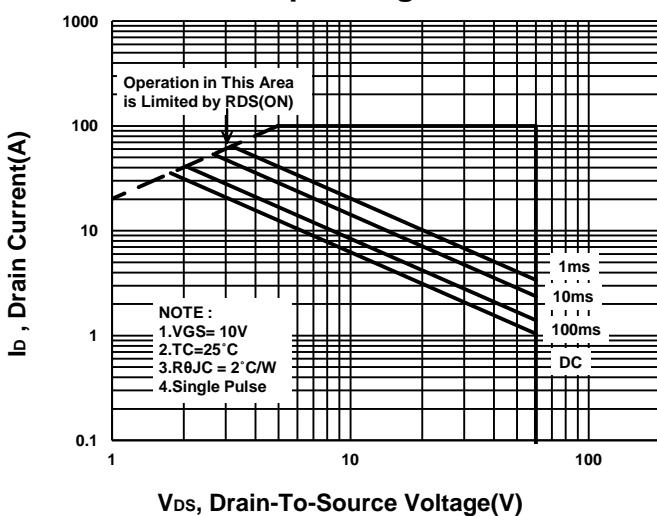
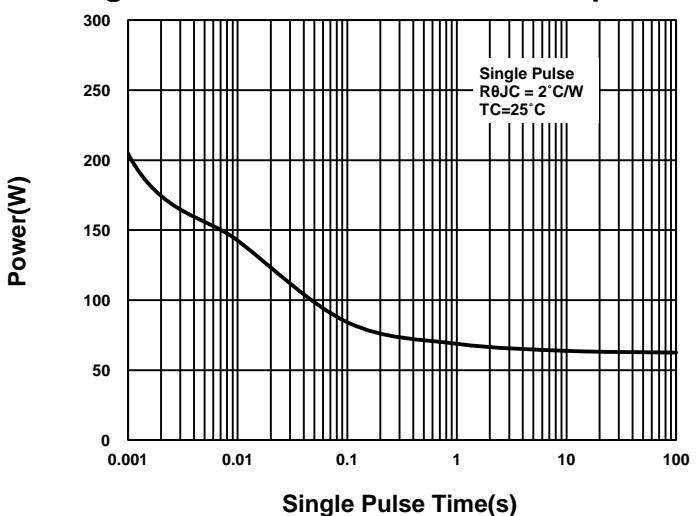


On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P2206BT
TO-220
Halogen-Free & Lead-Free****On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**